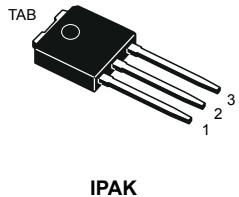


N-channel 800 V, 0.95 Ω typ., 6.5 A MDmesh Power MOSFET in an IPAK package

Features



| Order code | V _{DS} | R _{DS(on)} max. | I _D |
|------------|-----------------|--------------------------|----------------|
| STD7NM80-1 | 800 V | 1.05 Ω | 6.5 A |

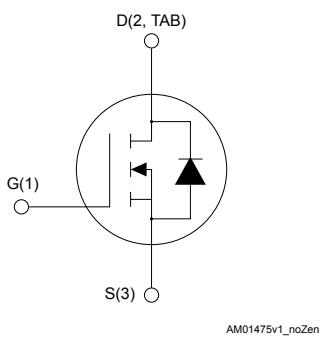
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Applications

- Switching applications

Description

This N-channel Power MOSFET is developed using STMicroelectronics' revolutionary MDmesh technology, which associates the multiple drain process with the company's PowerMESH horizontal layout. This device offers extremely low on-resistance, high dv/dt, and excellent avalanche characteristics. Using STMicroelectronics's proprietary strip technique, this Power MOSFET boasts an overall dynamic performance that is superior to similar products on the market.



Product status link

[STD7NM80-1](#)

Product summary

| | |
|------------|------------|
| Order code | STD7NM80-1 |
| Marking | D7NM80 |
| Package | IPAK |
| Packing | Tube |

1 Electrical ratings

Table 1. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|---|------------|------------------|
| V_{DS} | Drain-source voltage | 800 | V |
| V_{GS} | Gate-source voltage | ± 30 | V |
| I_D | Drain current (continuous) at $T_C = 25^\circ\text{C}$ | 6.5 | A |
| | Drain current (continuous) at $T_C = 100^\circ\text{C}$ | 4 | |
| $I_{DM}^{(1)}$ | Drain current (pulsed) | 26 | A |
| P_{TOT} | Total power dissipation at $T_C = 25^\circ\text{C}$ | 90 | W |
| T_{stg} | Storage temperature range | -55 to 150 | $^\circ\text{C}$ |
| T_J | Operating junction temperature range | | $^\circ\text{C}$ |

1. Pulse width is limited by safe operating area.

Table 2. Thermal data

| Symbol | Parameter | Value | Unit |
|------------|---|-------|---------------------------|
| R_{thJC} | Thermal resistance, junction-to-case | 1.4 | $^\circ\text{C}/\text{W}$ |
| R_{thJA} | Thermal resistance, junction-to-ambient | 100 | $^\circ\text{C}/\text{W}$ |

Table 3. Avalanche characteristics

| Symbol | Parameter | Value | Unit |
|----------|--|-------|------|
| I_{AS} | Avalanche current, repetitive or non-repetitive (pulse width limited by T_J max.) | 1 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_J = 25^\circ\text{C}$, $I_D = I_{AS}$, $V_{DD} = 50\text{ V}$) | 240 | mJ |

2 Electrical characteristics

$T_C = 25^\circ\text{C}$ unless otherwise specified.

Table 4. On/off states

| Symbol | Parameter | Test condition | Min. | Typ. | Max. | Unit |
|-----------------------------|-----------------------------------|---|------|------|-----------|---------------|
| $V_{(\text{BR})\text{DSS}}$ | Drain-source breakdown voltage | $I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$ | 800 | | | V |
| I_{DSS} | Zero gate voltage drain current | $V_{GS} = 0 \text{ V}, V_{DS} = 800 \text{ V}$ | | | 10 | μA |
| | | $V_{GS} = 0 \text{ V}, V_{DS} = 800 \text{ V}, T_C = 125^\circ\text{C}^{(1)}$ | | | 100 | |
| I_{GSS} | Gate body leakage current | $V_{DS} = 0 \text{ V}, V_{GS} = \pm 30 \text{ V}$ | | | ± 100 | nA |
| $V_{\text{GS}(\text{th})}$ | Gate threshold voltage | $V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$ | 3 | 4 | 5 | V |
| $R_{\text{DS}(\text{on})}$ | Static drain-source on-resistance | $V_{GS} = 10 \text{ V}, I_D = 3.25 \text{ A}$ | | 0.95 | 1.05 | Ω |

1. Specified by design, not tested in production.

Table 5. Dynamic

| Symbol | Parameter | Test condition | Min. | Typ. | Max. | Unit |
|------------------|------------------------------|--|------|------|------|----------|
| C_{iss} | Input capacitance | $V_{DS} = 50 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$ | - | 620 | - | pF |
| C_{oss} | Output capacitance | | - | 460 | - | pF |
| C_{rss} | Reverse transfer capacitance | | - | 15 | - | pF |
| R_g | Gate input resistance | $f = 1 \text{ MHz}$ open drain | - | 7 | - | Ω |
| Q_g | Total gate charge | $V_{DD} = 640 \text{ V}, I_D = 6.5 \text{ A}, V_{GS} = 0 \text{ to } 10 \text{ V}$ | - | 18 | - | nC |
| Q_{gs} | Gate-source charge | (see Figure 13. Test circuit for gate charge behavior) | - | 4 | - | nC |
| Q_{gd} | Gate-drain charge | | - | 11 | - | nC |

Table 6. Switching times

| Symbol | Parameter | Test condition | Min. | Typ. | Max. | Unit |
|---------------------|---------------------|---|------|------|------|------|
| $t_{d(\text{on})}$ | Turn-on delay time | $V_{DD} = 400 \text{ V}, I_D = 3.25 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ | - | 20 | - | ns |
| t_r | Rise time | | - | 8 | - | ns |
| $t_{d(\text{off})}$ | Turn-off delay time | | - | 35 | - | ns |
| t_f | Fall time | (see Figure 12. Test circuit for resistive load switching times and Figure 17. Switching time waveform) | - | 10 | - | ns |

Table 7. Source-drain diode

| Symbol | Parameter | Test condition | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|---|------|------|------|---------------|
| I_{SD} | Source-drain current | | - | | 6.5 | A |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | - | | 26 | A |
| $V_{SD}^{(2)}$ | Forward on voltage | $I_{SD} = 6.5 \text{ A}, V_{GS} = 0 \text{ V}$ | - | | 1.3 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 6.5 \text{ A}, dI/dt = 100 \text{ V}$ | - | 460 | | ns |
| Q_{rr} | Reverse recovery charge | $V_{DD} = 50 \text{ V}$ (see Figure 14. Test circuit for inductive load switching and diode recovery times) | - | 4 | | μC |
| I_{RRM} | Reverse recovery current | | - | 17 | | A |
| t_{rr} | Reverse recovery time | $I_{SD} = 6.5 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$ | - | 680 | | ns |
| Q_{rr} | Reverse recovery charge | $V_{DD} = 50 \text{ V}$ (see Figure 14. Test circuit for inductive load switching and diode recovery times) | - | 6 | | μC |
| I_{RRM} | Reverse recovery current | | - | 17 | | A |

1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%.

Obsolete Product(s) - Obsolete Product(s)

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

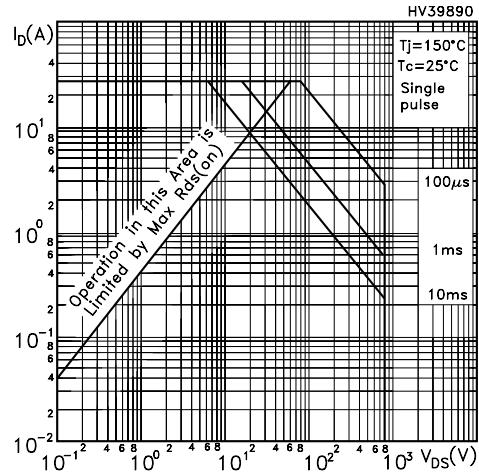


Figure 2. Thermal impedance

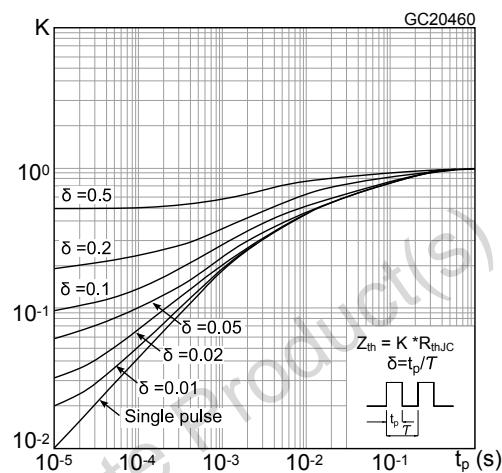


Figure 3. Output characteristics

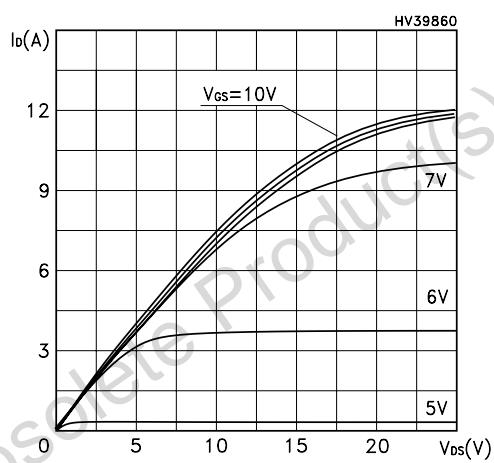


Figure 4. Transfer characteristics

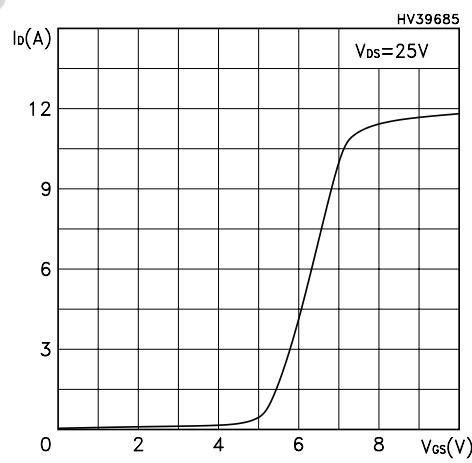


Figure 5. Static drain-source on-resistance

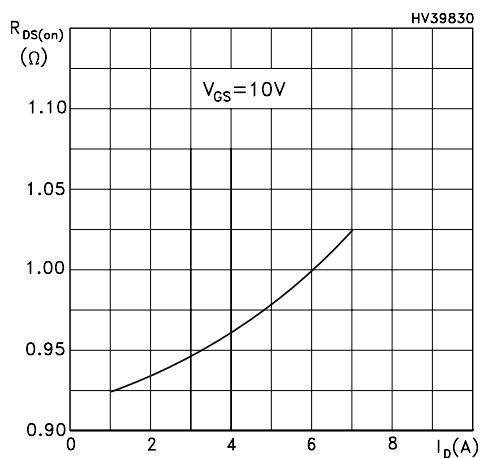


Figure 6. Gate charge vs gate-source voltage

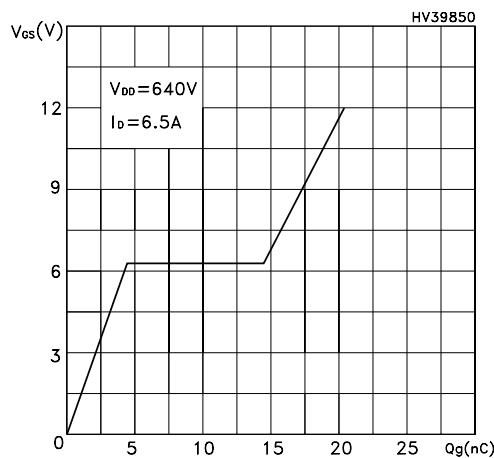
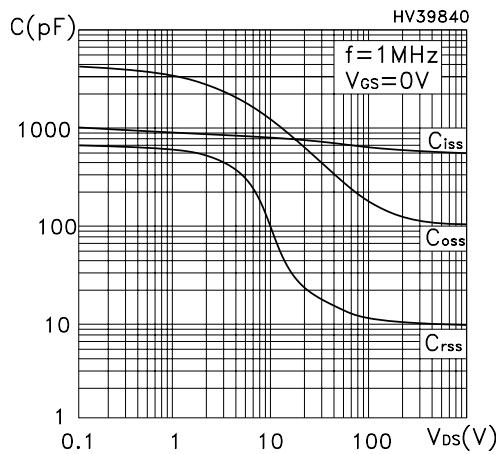
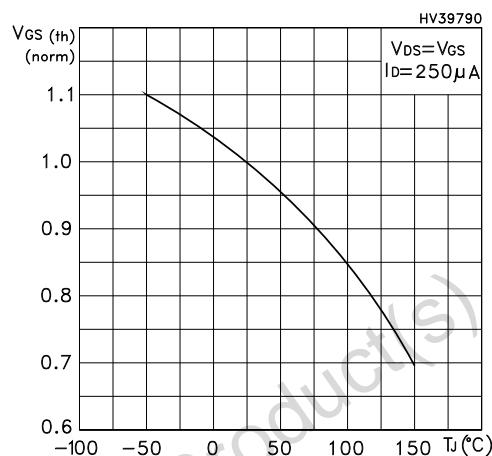
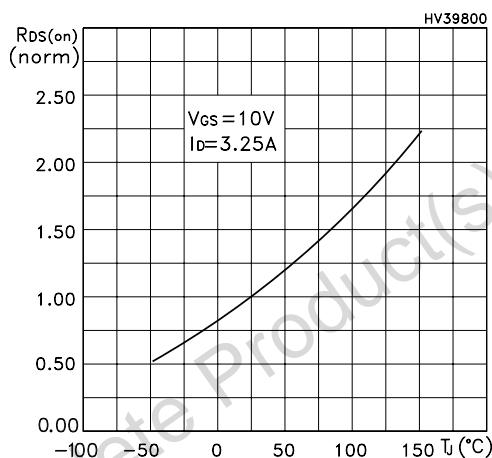
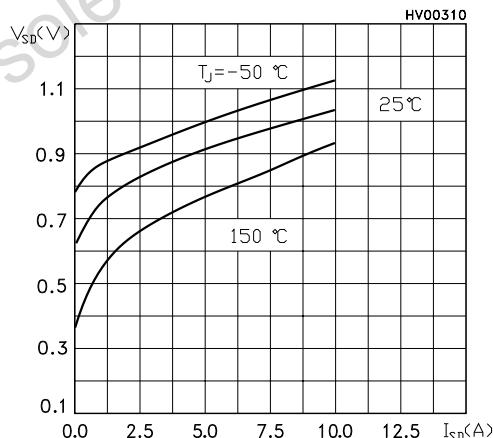
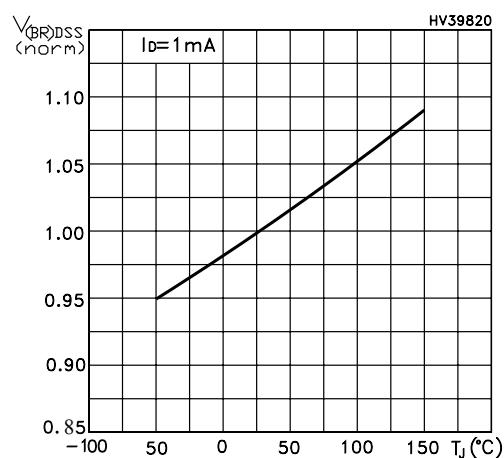
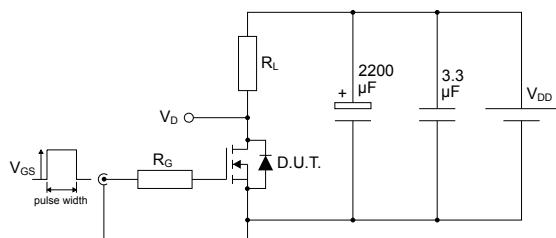


Figure 7. Capacitance variations

Figure 8. Normalized gate threshold voltage vs temperature

Figure 9. Normalized on-resistance vs temperature

Figure 10. Source-drain diode forward characteristics

Figure 11. Normalized $V_{(BR)DSS}$ vs temperature


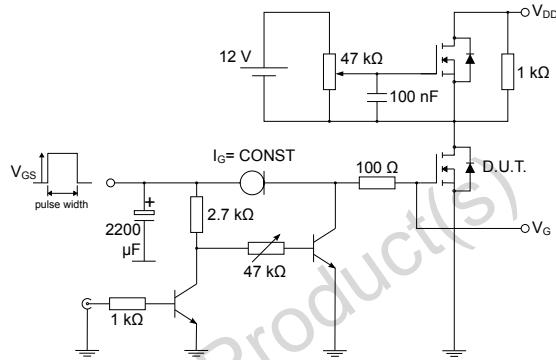
3 Test circuits

Figure 12. Test circuit for resistive load switching times



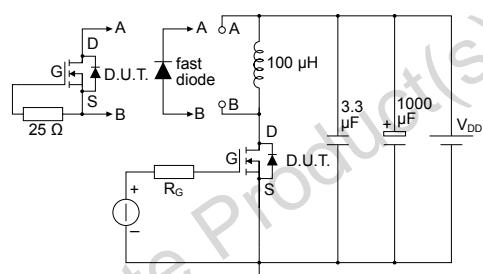
AM01468v1

Figure 13. Test circuit for gate charge behavior



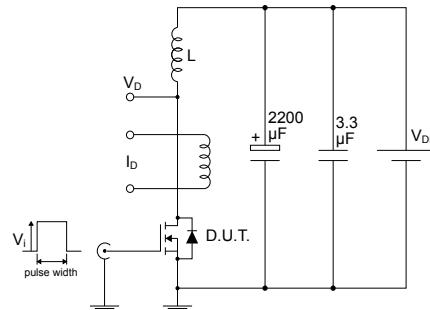
AM01469v1

Figure 14. Test circuit for inductive load switching and diode recovery times



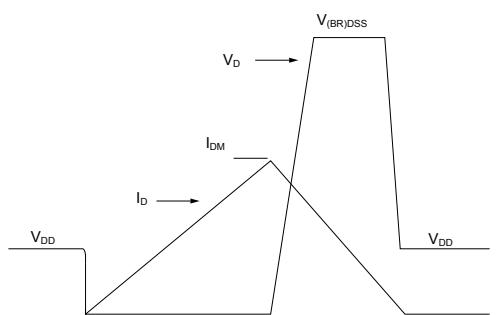
AM01470v1

Figure 15. Unclamped inductive load test circuit



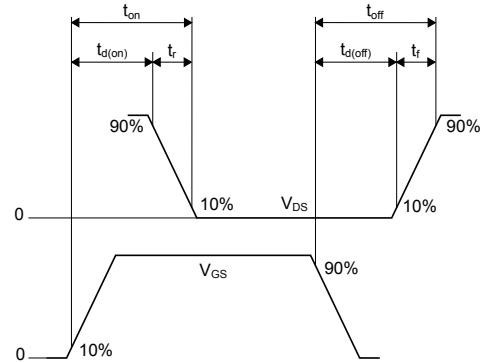
AM01471v1

Figure 16. Unclamped inductive waveform



AM01472v1

Figure 17. Switching time waveform



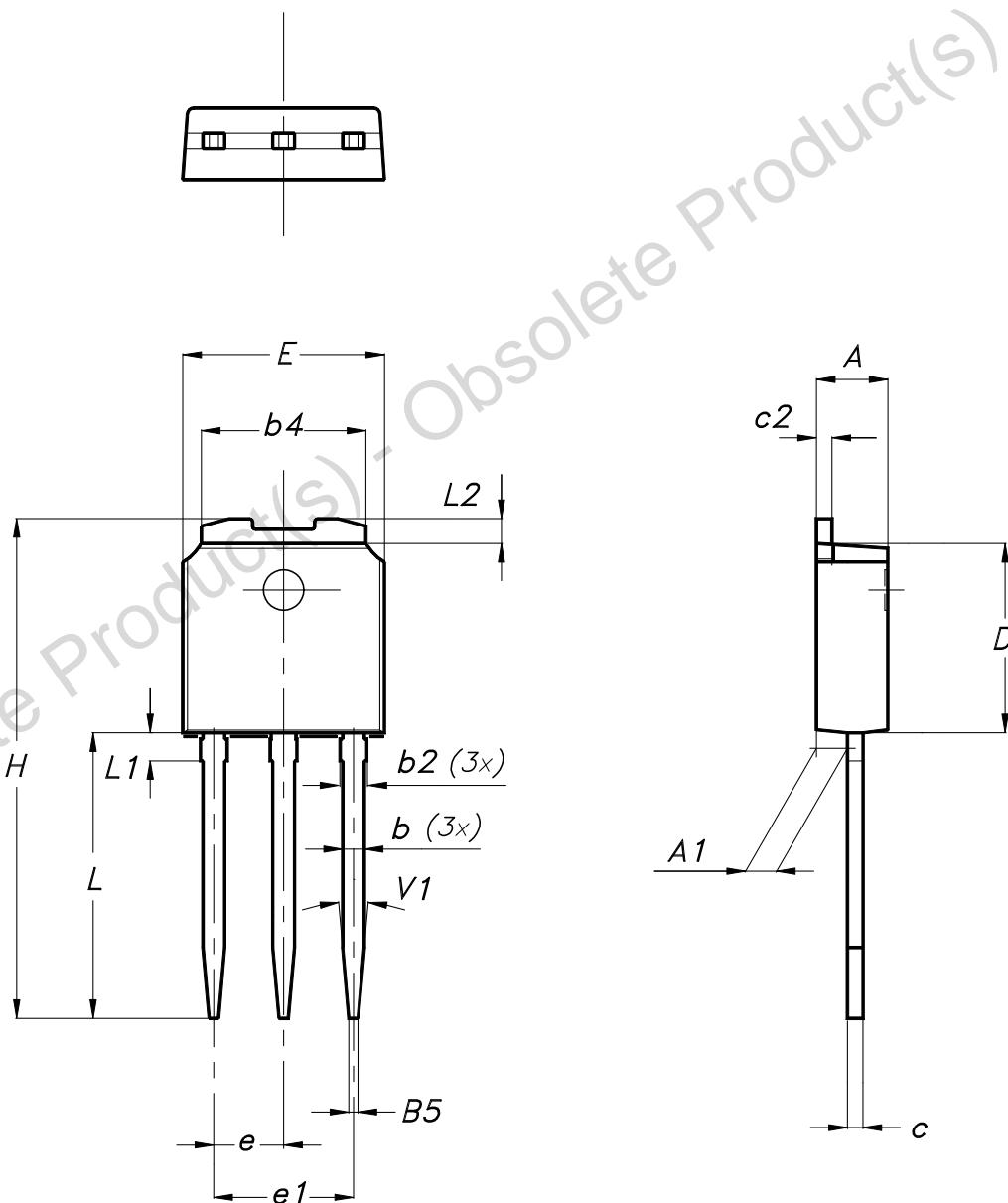
AM01473v1

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 IPAK (TO-251) type A package information

Figure 18. IPAK (TO-251) type A package outline



0068771_A_rev.16

Table 8. IPAK (TO-251) type A package mechanical data

| Dim. | mm | | |
|------|------|-------|------|
| | Min. | Typ. | Max. |
| A | 2.20 | | 2.40 |
| A1 | 0.90 | | 1.10 |
| b | 0.64 | | 0.90 |
| b2 | | | 0.95 |
| b4 | 5.20 | | 5.40 |
| B5 | | 0.30 | |
| c | 0.45 | | 0.60 |
| c2 | 0.48 | | 0.60 |
| D | 6.00 | | 6.20 |
| E | 6.40 | | 6.60 |
| e | | 2.28 | |
| e1 | 4.40 | | 4.60 |
| H | | 16.10 | |
| L | 9.00 | | 9.40 |
| L1 | 0.80 | | 1.20 |
| L2 | | 0.80 | 1.00 |
| V1 | | 10° | |

Obsolete Product(s) - Obsolete Product(s)

Revision history

Table 9. Document revision history

| Date | Revision | Changes |
|-------------|----------|--|
| 30-May-2023 | 1 | First release. The part number STD7NM80-1 was previously inserted in the DS4854. |

Obsolete Product(s) - Obsolete Product(s)

Contents

| | | |
|------------|---|-----------|
| 1 | Electrical ratings | 2 |
| 2 | Electrical characteristics..... | 3 |
| 2.1 | Electrical characteristics (curves) | 5 |
| 3 | Test circuits | 7 |
| 4 | Package information..... | 8 |
| 4.1 | IPAK (TO-251) type A package information..... | 8 |
| | Revision history | 10 |

Obsolete Product(s) - Obsolete Product(s)

IMPORTANT NOTICE – READ CAREFULLY

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgment.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. For additional information about ST trademarks, refer to www.st.com/trademarks. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2023 STMicroelectronics – All rights reserved

Obsolete Product(s) - Obsolete Product(s)